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PATENT APPLICATION

IN THE U.S. PATENT AND TRADEMARK OFFICE

Applicant: Takashi DATE et al  
Title : HEAT-SENSITIVE RECORDING MATERIAL

Serial No. : 10/551 675 Group: 2854  
Confirmation No.: 5519  
Filed : September 29, 2005 Examiner: Unknown  
International Application No.: PCT/JP2004/004667  
International Filing Date : March 31, 2004  
Atty. Docket No.: 4364.P0013US

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

FIRST CLASS MAILING CERTIFICATE

Sir:

I hereby certify that this correspondence is being deposited with the United States Postal Service under 37 CFR 1.8 as first class mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on December 4, 2006.

  
Terryence F. Chapman

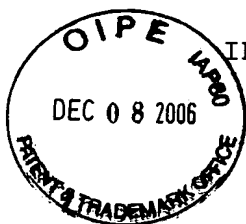
TFC/ps

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Correspondence: Information Disclosure Statement dated December 4, 2006, with enclosures listed thereon

190.05/05

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INFORMATION DISCLOSURE STATEMENT

Sir:

In compliance with the provisions of Rules 1.97(b)(3) and 1.98, enclosed herewith is a copy of the European Patent Office Supplementary Search Report for the foreign patent application corresponding to the present application, Form PTO-1449 and the non-U.S. references cited thereon. Copies of cited U.S. references are not submitted in accordance with 37 CFR 1.98(a).

Where necessary, the requirement for a concise explanation of relevance of any enclosed non-English reference is satisfied by the enclosed European Patent Office Search Report. Further comment at this point in time should not be necessary.

Further consideration is respectfully solicited.

Respectfully submitted,

TFC/ps

  
Terryence F. Chapman

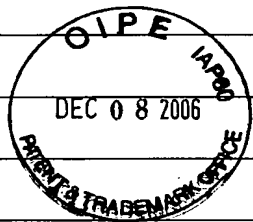
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Encl: Copy of European Patent Office Supplementary Search  
Report dated September 19, 2006 (2 pages)  
Form PTO-1449 and non-U.S. references cited thereon  
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INFORMATION DISCLOSURE CITATION	Applicant: Takashi DATE et al
	Ser.No.: 10/551 675      Filed: September 29, 2005
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	Group: 2854      Date: December 4, 2006

## U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No.	Document Number - Kind Code	Publication Date MM-DD-YYYY	Name of Patentee or Applicant
	AA	US 2 900 348	08-18-1959	AHLBERG, et al.
	AB			
	AC			
	AD			



## FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No.	Country Code - Document Number - Kind Code	Publication Date MM-DD-YYYY	Name of Patentee or Applicant	Trans.
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	AF	EP 0 326 964 A2	01-27-1989	ISHIDA, et al.	
	AG	JP 2002-301873	10-15-2002	SHINICHI, et al.	Abstract, Description
	AH	JP 10-258577	09-29-1998	CHUICHI, et al.	
	AI	JP 09-266711	10-14-1997	YOSHIKANE, et al.	
	AJ	JP 09-207435	08-12-1997	TOSHIKI, et al.	Abstract, Claims
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	AM	JP 55-159993	12-12-1980	HISASHI	Abstract
	AN	WO 02/081229 A1	10-17-2002	KAWAKAMI, et al.	Abstract
	AO	WO 00/15552 A1	03-23-2000	HANABUSA, et al.	Abstract
	AP	WO 97/16420 A1	05-09-1997	SATO, et al.	Abstract

## NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No.	(Include Author, Title, Date, Pages, Etc.)
	AQ	
	AR	
EXAMINER SIGNATURE		DATE CONSIDERED

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.